

**In the Abstract**

Please amend the Abstract as follows:

~~The invention relates to a~~ A device and a method for predicting the mean time period between two failures of a technical system, for example a manufacturing system or an assembly system for motor vehicle components. The device includes ~~comprises~~ a components list (130.1, 130.2). Those components of the technical system which are included in this components list are the maintenance-intensive components. Every failure of a component of the list leads to a failure of the system. Furthermore, the device ~~includes~~ ~~comprises~~ an apparatus for acquiring setpoint MTBF values of all the components of the list. A setpoint MTBF value of a component is a requested or planned mean time period between two failures of this component. The apparatus predicts the planned mean time period between two failures of the technical system as a function of the setpoint MTBF values of the components. ~~The invention provides a method and a device for predicting at low cost the failure frequencies occurring during the entire period of use of a technical system.~~

(~~Fig. 1~~)